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PATENT

NEW CLAIMS FOR SERIAL NO. 09/624,656

28. (New) The method of claim 5, wherein determining the thickness of said layer of refractory metal based upon the single measurement of said layer of refractory metal comprises determining the thickness of said layer of refractory metal based upon the single measurement of said layer of refractory metal performed by a metrology tool.

29. (New) The method of claim 6, wherein determining the thickness of said layer of refractory metal based upon multiple measurements of said layer of refractory metal comprises determining the thickness of said layer of refractory metal based upon multiple measurements of said layer of refractory metal performed by a metrology tool.

30. (New) The method of claim 14, wherein determining the thickness of said layer of refractory metal based upon the single measurement of said layer of refractory metal comprises determining the thickness of said layer of refractory metal based upon the single measurement of said layer of refractory metal performed by a metrology tool.

31. (New) The method of claim 15, wherein determining the thickness of said layer of refractory metal based upon multiple measurements of said layer of refractory metal comprises determining the thickness of said layer of refractory metal based upon multiple measurements of said layer of refractory metal performed by a metrology tool.

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